Receipt date: 05/09/2006 107/5878 6/9/31795

IAP12 Rec'd PCT/PTO 09 MAY 2006

Customer No. 22,852 Attorney Docket No. 05823.0283

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re A	pplication of:)
Hai W	on LEE et al.)
Applic	ation No.: Not Yet Assigned) Group Art Unit:)) Examiner:
Filed:	May 9, 2006)
For:	FABRICATION METHOD OF EXTREME ULTRAVIOLET RATION MASK MIRROR USING ATOMIC FORCE MICROSCOPE LITHOGRAPHY	; ; ;

U.S. National Phase of International PCT Application No. PCT/KR2004/001363

MAIL STOP PCT Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

INFORMATION DISCLOSURE STATEMENT UNDER 37 C.F.R. § 1.97(b)

Pursuant to 37 C.F.R. §§1.56 and 1.97(b), applicants bring to the Examiner's attention the documents listed on attached Form PTO/SB/08 and cited in the enclosed international search report. Copies of the listed foreign patent document and listed non patent literature documents are attached. Applicants respectfully request that the Examiner consider the documents listed on attached Form PTO/SB/08 and indicate that they were considered by making an appropriate notation on this form.

This Information Disclosure Statement is being filed with the above-referenced application.

Receipt date: 05/09/2006 10-7/65878 (6/8)31795

IAP12 Rec'd PCT/PTO 0.9 MAY 2006

Attorney Docket No. 05823.0283

This submission does not represent that a search has been made or that no better art exists and does not constitute an admission that each or all of the listed documents are material or constitute "prior art." If the Examiner applies any of the documents as prior art against any claim in the application and applicants determine that the cited documents do not constitute "prior art" under United States law, applicants reserve the right to present to the Office the relevant facts and law regarding the appropriate status of such documents. Applicants further reserve the right to take appropriate action to establish the patentability of the disclosed invention over the listed documents, should one or more of the documents be applied against the claims of the present application.

If there is any fee due in connection with the filing of this Statement, please charge the fee to our Deposit Account No. 06-0916.

Respectfully submitted,

FINNEGAN, HENDERSON, FARABOW, GARRETT & DUNNER, L.L.P.

Dated: May 9, 2006

Ernest F. Chapman Reg. No. 25,961

Enclosures EFC/FPD/gah Receipt date: 05/09/2006 IAP12 Rec'd PC7

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IDS Form PTO/SB/08: Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT		Complete if AnDw/ 578683			
				Application Number	
INFORMATION DISCLOSURE				Filing Date	May 9, 2006
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)		First Named Inventor	Hai Won LEE		
STATEMENT BY APPLICANT			14.1	Art Unit	
(Use as many sheets as necessary)				Examiner Name	
Sheet	1	of	1	Attorney Docket Number	05823.0283

	U.S. PATENTS AND PUBLISHED U.S. PATENT APPLICATIONS					
Examiner Cite Initials No.		Document Number	Issue or	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where	
	No.'	Number-Kind Code ² (if known)	Publication Date MM-DD-YYYY		Relevant Passages or Relevant Figures Appear	
		US-6,110,607	09-29-2000	Montcalm et al.		
		US-6,229,652 B1	05-08-2001	Bajt et al.		
		US-6,228,512 B1	05-08-2001	Bajt et al.		
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Note: Copies of the U.S. Patent Documents are not Required in IDS filed after October 21, 2004

	FOREIGN PATENT DOCUMENTS						
Examiner Initials	Cite No.1	Foreign Patent Document Country Code ³ Number ⁴ Kind Code ⁵ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	Translation ⁶	
	L			<u> </u>			

Cite No. ¹	Include name of the author (in CAPITAL LETTERS), tille of the article (when appropriate), tille of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	Translation
	RYU; "METHOD FOR MANUFACTURING A SEMICONDUCTOR DEVICE"; Korean Patent Abstracts of KR 102000073498 A, May 12, 2000.	
	MATSUO et al.; "MANUFACTURE OF MASK FOR EXPOSURE TO X-RAY AND BLANK USED THEREWITH"; Patent Abstracts of Japan of JP 05-283323, October 29, 1993	
	SUNDERMANN et al.; "NANOPATTERNING OF AU ABSORBER FILMS ON Mo/SI EUV MULTILAYER MIRRORS BY STM LITHOGRAPHY IN SELF-ASSEMBLED MONOLAYERS", Surface Science, Vol. 454-456, pages 1104-1109, (2000)	
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	Cite No.1	No.¹ (book, magazine, journal, senial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, vily and/or country where published. RYU: "METHOD FOR MANUFACTURING A SEMICONDUCTOR DEVICE"; Korean Patent Abstracts of KR 1202000073498 A, May 12, 2000. MATSUO et al.; "MANUFACTURE OF MASK FOR EXPOSURE TO X-RAY AND BLANK USED THEREWITH*, Patent Abstracts of Japan of JP 05-283232, October 29, 1993 SUNDERMANN et al.; "NANOPATTERNING OF AN ASSORBER FILMS ON MOSI EUV MULTILAYER MIRRORS BY STM LITHOGRAPHY IN SELF. ASSEMBLE OM MONOLAYERS; Surface Science, Vol. 454-

Examiner Signature	/Stephen Rosasco/	Date Considered	11/13/2008	

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /SR/